

## 2SK1835

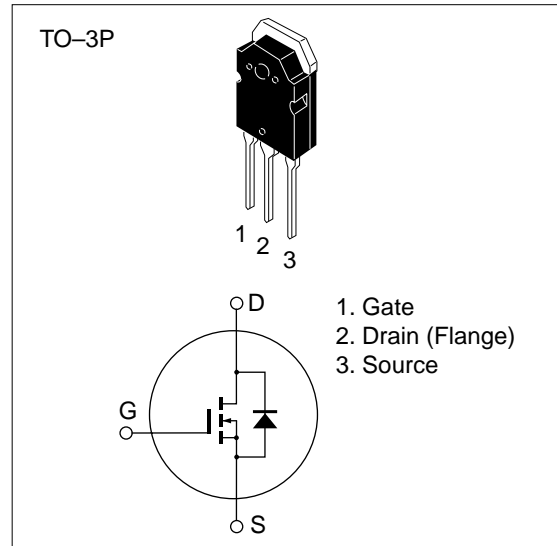
### Silicon N Channel MOS FET

#### Application

High speed power switching

#### Features

- High breakdown voltage ( $V_{DSS} = 1500V$ )
- High speed switching
- Low drive current
- No secondary breakdown
- Suitable for switching regulator



**Table 1 Absolute Maximum Ratings** ( $T_a = 25^\circ C$ )

Item	Symbol	Ratings	Unit
Drain to source voltage	$V_{DSS}$	1500	V
Gate to source voltage	$V_{GSS}$	$\pm 20$	V
Drain current	$I_D$	4	A
Drain peak current	$I_{D(pulse)^*}$	10	A
Body-drain diode reverse drain current	$I_{DR}$	4	A
Channel dissipation	$P_{ch}^{**}$	125	W
Channel temperature	$T_{ch}$	150	$^\circ C$
Storage temperature	$T_{stg}$	-55 to +150	$^\circ C$

\*  $PW \leq 10 \mu s$ , duty cycle  $\leq 1\%$

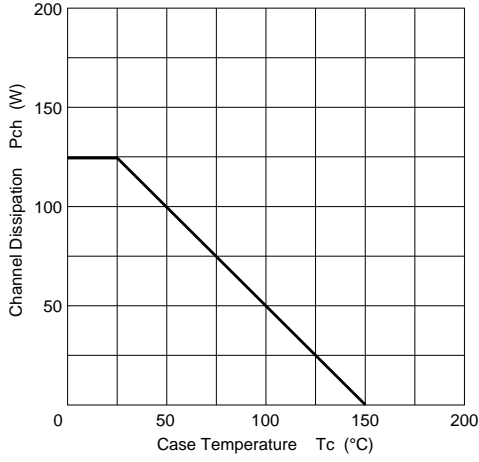
\*\* Value at  $T_c = 25^\circ C$

**Table 2 Electrical Characteristics** (Ta = 25°C)

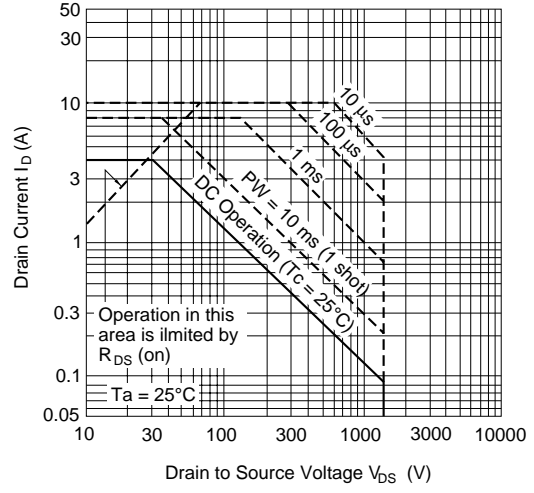
Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Drain to source breakdown voltage	$V_{(BR)DSS}$	1500	—	—	V	$I_D = 10 \text{ mA}$ , $V_{GS} = 0$
Gate to source leak current	$I_{GSS}$	—	—	±1	μA	$V_{GS} = \pm 20 \text{ V}$ , $V_{DS} = 0$
Zero gate voltage drain current	$I_{DSS}$	—	—	500	μA	$V_{DS} = 1200 \text{ V}$ , $V_{GS} = 0$
Gate to source cutoff voltage	$V_{GS(off)}$	2.0	—	4.0	V	$I_D = 1 \text{ mA}$ , $V_{DS} = 10 \text{ V}$
Static drain to source on state resistance	$R_{DS(on)}$	—	4.6	7.0	Ω	$I_D = 2 \text{ A}$ $V_{GS} = 15 \text{ V}^*$
Forward transfer admittance	$ y_{fs} $	0.9	1.4	—	S	$I_D = 2 \text{ A}$ $V_{DS} = 20 \text{ V}^*$
Input capacitance	$C_{iss}$	—	1700	—	pF	$V_{DS} = 10 \text{ V}$
Output capacitance	$C_{oss}$	—	230	—	pF	$V_{GS} = 0$
Reverse transfer capacitance	$C_{rss}$	—	100	—	pF	$f = 1 \text{ MHz}$
Turn-on delay time	$t_{d(on)}$	—	25	—	ns	$I_D = 2 \text{ A}$
Rise time	$t_r$	—	80	—	ns	$V_{GS} = 10 \text{ V}$
Turn-off delay time	$t_{d(off)}$	—	230	—	ns	$R_L = 15 \Omega$
Fall time	$t_f$	—	80	—	ns	
Body-drain diode forward voltage	$V_{DF}$	—	0.85	—	V	$I_F = 4 \text{ A}$ , $V_{GS} = 0$
Body-drain diode reverse recovery time	$t_{rr}$	—	2500	—	ns	$I_F = 4 \text{ A}$ , $V_{GS} = 0$ , $di_F / dt = 100 \text{ A} / \mu\text{s}$

\* Pulse Test

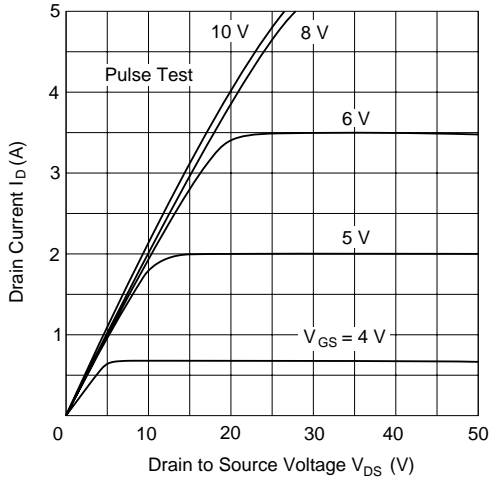
Power vs. Temperature Derating



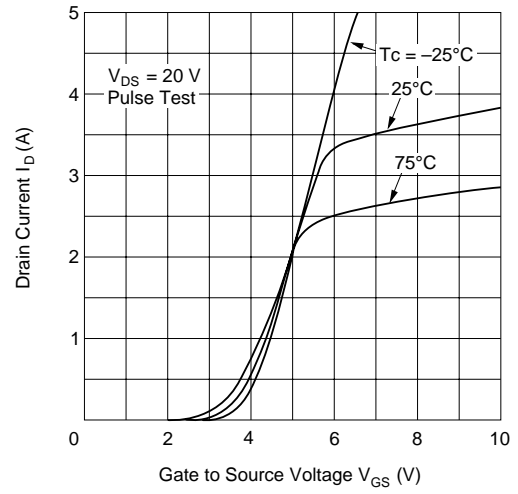
Maximum Safe Operation Area



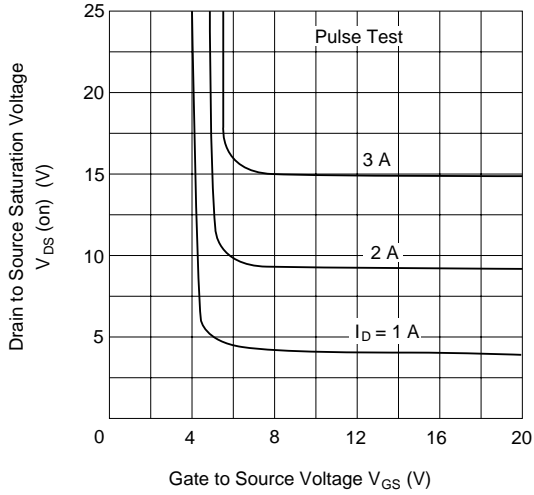
Typical Output Characteristics



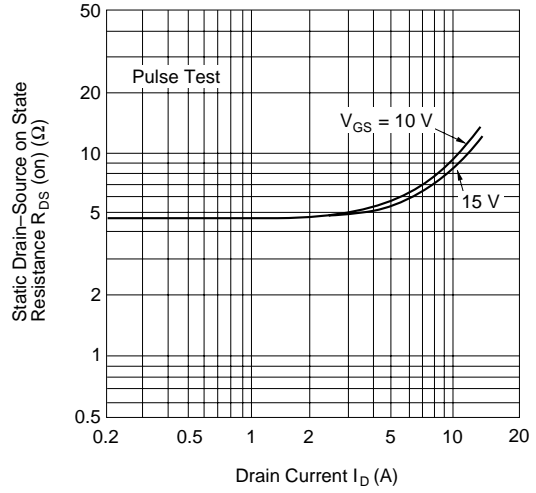
Typical Transfer Characteristics



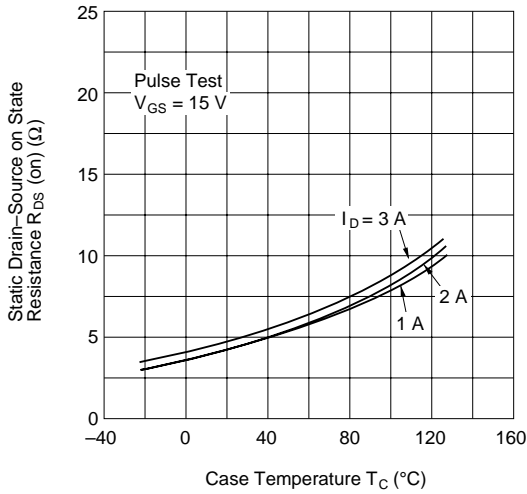
Drain-Source Saturation Voltage vs. Gate-Source Voltage



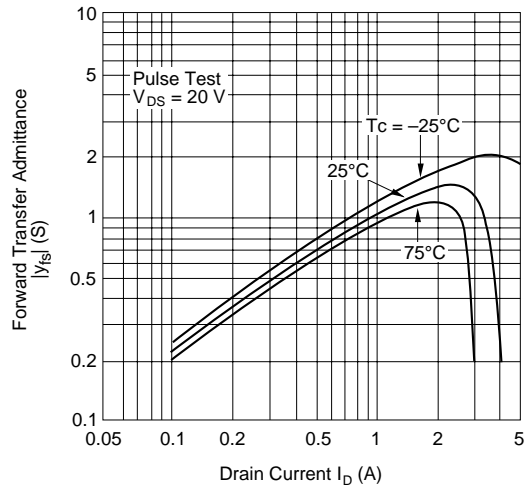
Static Drain-Source on State Resistance vs. Drain Current



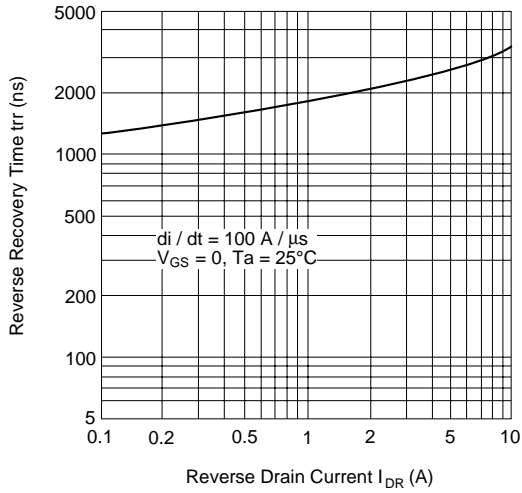
Static Drain-Source on State Resistance vs. Temperature



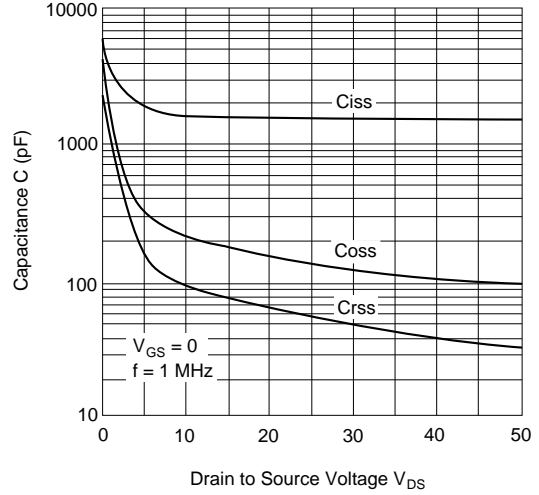
Forward Transfer Admittance vs. Drain Current



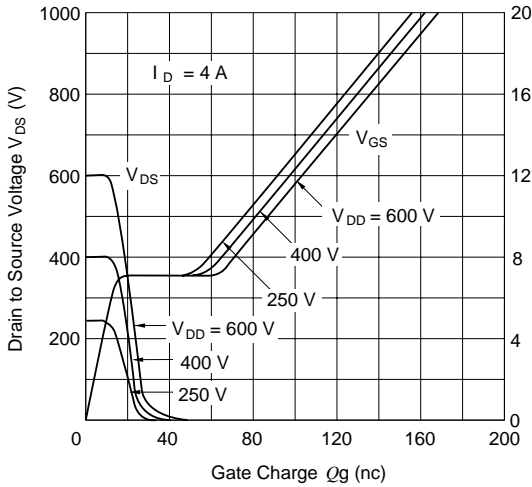
Body-Drain Diode Reverse Recovery Time



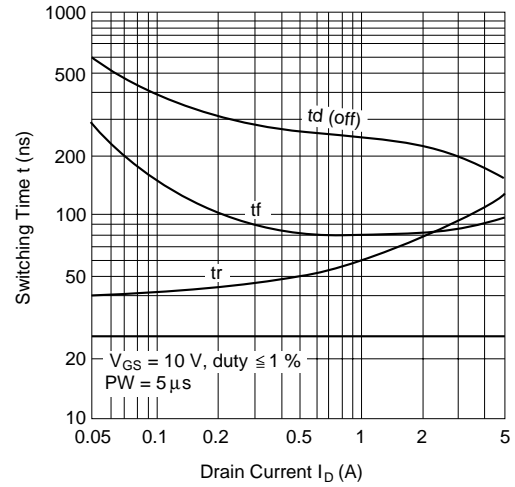
Typical Capacitance vs. Drain-Source Voltage



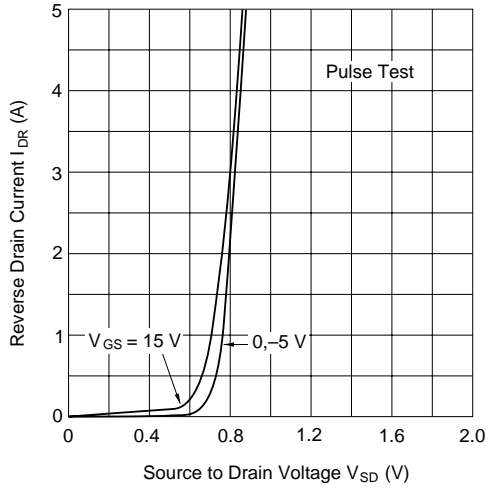
Dynamic Input Characteristics



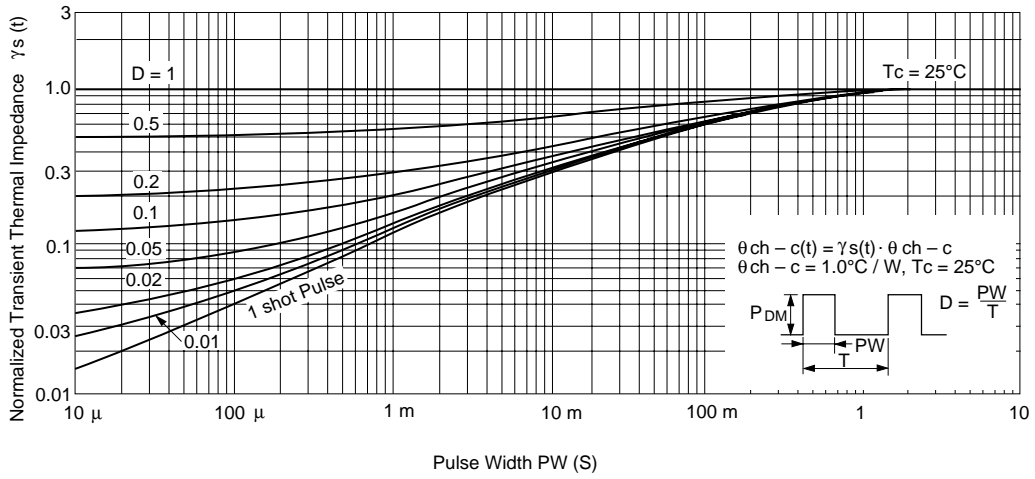
Switching Characteristics



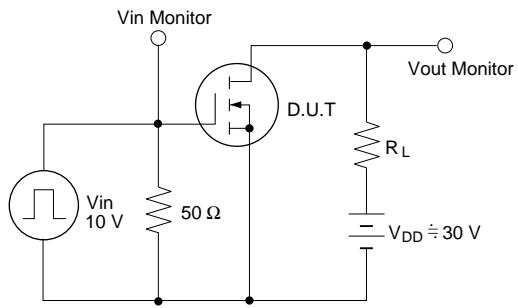
Reverse Drain Current vs. Source to Drain Voltage



Normalized Transient Thermal Impedance vs. Pulse Width



Switching Time Test Circuit



Waveforms

